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DCR2220Y65

Phase Control Thyristor

Preliminary Information

DS5835-1.3 June 2008 (LN26217)

FEATURES

- **Double Side Cooling**
- High Surge Capability

APPLICATIONS

- **High Power Drives** •
- High Voltage Power Supplies
- Static Switches

VOLTAGE RATINGS

Part and Ordering Number	Repetitive Peak Voltages V _{DRM} and V _{RRM} V	Conditions		
DCR2220Y65* DCR2220Y60 DCR2220Y55 DCR2220Y50	6500 6000 5500 5000	$\begin{array}{l} T_{vj} = -40 \ \mbox{°C} \ to \ 125 \ \mbox{°C}, \\ I_{DRM} = I_{RRM} = 300 \ \mbox{MA}, \\ V_{DRM}, V_{RRM} \ t_p = 10 \ \mbox{ms}, \\ V_{DSM} \& \ V_{RSM} = \\ V_{DRM} \& \ V_{RRM} \ + 100 \ \ \ respectively \end{array}$		

Lower voltage grades available. * 6200V @ -40° C, 6500V @ 0° C

ORDERING INFORMATION

When ordering, select the required part number shown in the Voltage Ratings selection table.

For example:

DCR2220Y65

Note: Please use the complete part number when ordering and quote this number in any future correspondence relating to your order.

KEY PARAMETERS

V _{DRM}	6500V
I _{T(AV)}	2220A
ITSM	30000A
dV/dt*	1500V/μs
dl/dt	300A/µs

* Higher dV/dt selections available

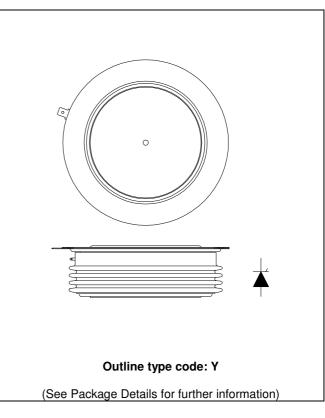


Fig. 1 Package outline



CURRENT RATINGS

 T_{case} = 60 °C unless stated otherwise

Symbol	Parameter	Test Conditions		Units
Double Side Cooled				
I _{T(AV)}	Mean on-state current	Half wave resistive load	2220	А
I _{T(RMS)}	RMS value	-	3487	А
Ι _Τ	Continuous (direct) on-state current	-	3270	А

SURGE RATINGS

Symbol	Parameter	Test Conditions	Max.	Units
I _{TSM}	Surge (non-repetitive) on-state current	10ms half sine, $T_{case} = 125 \text{°C}$	30.0	kA
l ² t	I ² t for fusing	$V_{R} = 0$	4.50	MA ² s

THERMAL AND MECHANICAL RATINGS

Symbol	Parameter	Test Conditions		Min.	Max.	Units
R _{th(j-c)}	Thermal resistance – junction to case	Double side cooled	DC	-	0.00835	℃/W
		Single side cooled	Anode DC	-	0.0134	℃/W
			Cathode DC	-	0.023	°C/W
R _{th(c-h)}	Thermal resistance – case to heatsink	Clamping force 54.0kN	Double side	-	0.002	°C/W
		(with mounting compound)	Single side	-	0.004	°C/W
T_{vj}	Virtual junction temperature	On-state (conducting)		-	135	°C
		Reverse (blocking)		-	125	°C
T _{stg}	Storage temperature range			-55	125	°C
Fm	Clamping force			48	59	kN



DYNAMIC CHARACTERISTICS

Symbol	Parameter	Test Conditions		Min.	Max.	Units
I _{RRM} /I _{DRM}	Peak reverse and off-state current	At V _{RRM} /V _{DRM} , T _{case} = 125 ℃		-	300	mA
dV/dt	Max. linear rate of rise of off-state voltage	To 67% V _{DRM} , T _j = 125℃, ga	ate open	-	1500	V/µs
dl/dt	Rate of rise of on-state current	From 67% V_{DRM} to 2x $I_{\text{T}(\text{AV})}$	Repetitive 50Hz	-	150	A/µs
		Gate source 30V, 10Ω,	Non-repetitive	-	300	A/µs
		tr < 0.5µs, Tj = 125 ℃				
V _{T(TO)}	Threshold voltage – Low level	500A to 3000A at $T_{case} = 125$	5℃	-	1.0	V
	Threshold voltage – High level	3000A to 7200A at T _{case} = 125 ℃		-	1.237	V
r _T	On-state slope resistance – Low level	500A to 3000A at T _{case} = 125 ℃		-	0.4286	mΩ
	On-state slope resistance – High level	3000A to 7200A at T _{case} = 125 ℃		-	0.3518	mΩ
t _{gd}	Delay time	$V_D = 67\% V_{DRM}$, gate source 30V, 10 Ω		-	3	μs
		$t_r = 0.5 \mu s, T_j = 25 ^{\circ}C$				
t _q	Turn-off time	$T_j = 125 ^{\circ}C, V_R = 200V, dI/dt = 1A/\mu s,$		-	1200	μs
		$dV_{DR}/dt = 20V/\mu s$ linear				
Qs	Stored charge	$I_T = 2000A, T_j = 125 ^{\circ}C, dI/dt - 1A/\mu s,$		2400	6000	μC
ΙL	Latching current	$T_j = 25 ^{\circ}\text{C}, V_D = 5V$		-	3	А
Ι _Η	Holding current	$T_j = 25 ^{\circ}C, \ R_{G-K} = \infty, \ I_{TM} = 500A, \ I_T = 5A$		-	300	mA





Symbol	Parameter	Test Conditions	Max.	Units
V _{GT}	Gate trigger voltage	V _{DRM} = 5V, T _{case} = 25℃	1.5	V
V _{GD}	Gate non-trigger voltage	At 50% V _{DRM,} T _{case} = 125 ℃	0.4	V
I _{GT}	Gate trigger current	V _{DRM} = 5V, T _{case} = 25℃	250	mA
I _{GD}	Gate non-trigger current	At 50% V _{DRM,} T _{case} = 125 ℃	15	mA

CURVES

) ***Nex SEMICONDUCTOR

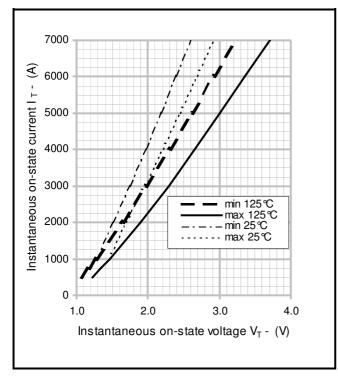


Fig.2 Maximum & minimum on-state characteristics

V_{TM} EQUATION

Where A = 0.537658B = 0.064222 $V_{TM} = A + Bln (I_T) + C.I_T + D.\sqrt{I_T}$ C = 0.000301D = 0.005935these values are valid for $T_j = 125\,^\circ\!\!\mathrm{C}$ for I_T 100A to 7200A



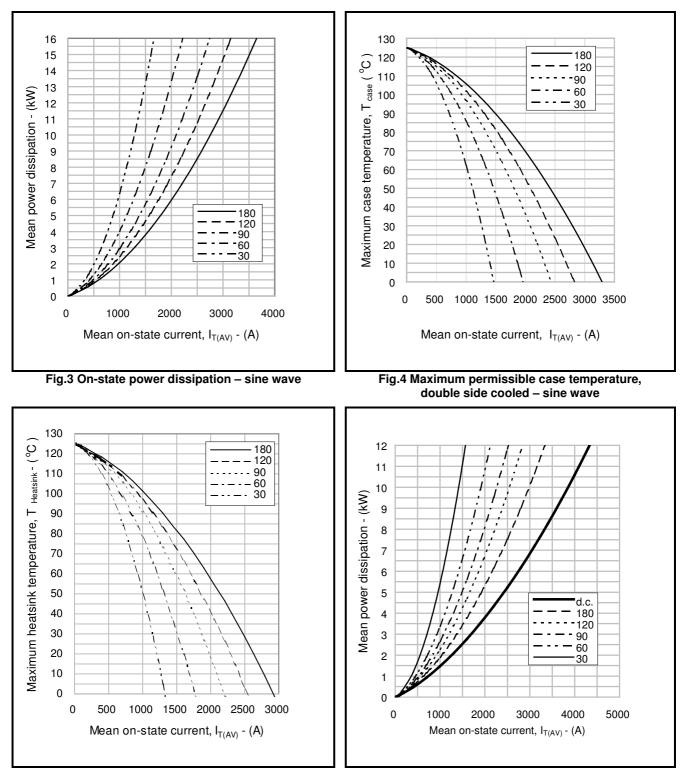


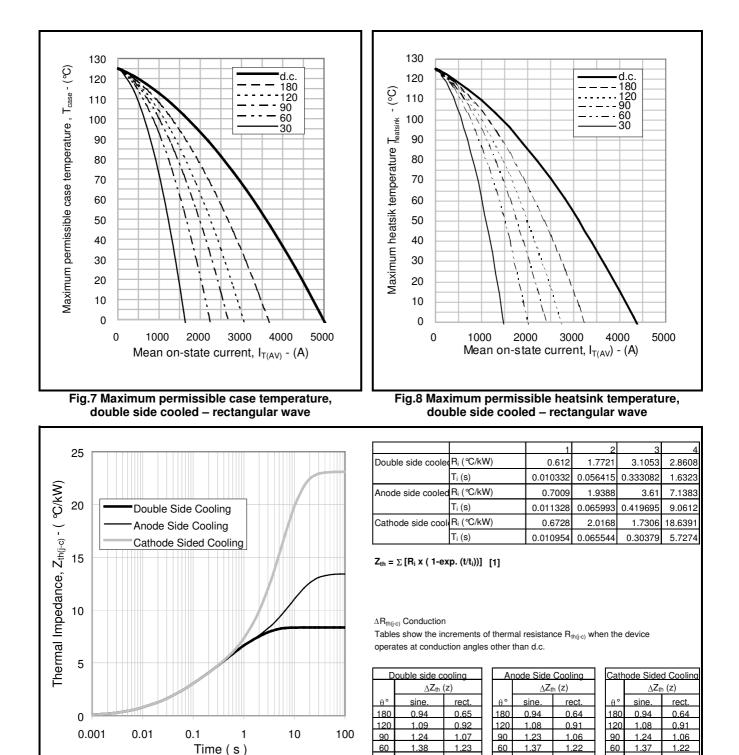
Fig.5 Maximum permissible heatsink temperature, double side cooled – sine wave

Fig.6 On-state power dissipation - rectangular wave

DCR2220Y65

ion Implant







30

15

1.49

1.54

1.40

1.49

30

15

1.47

1.52

1.38

1.47

30

15

1.48

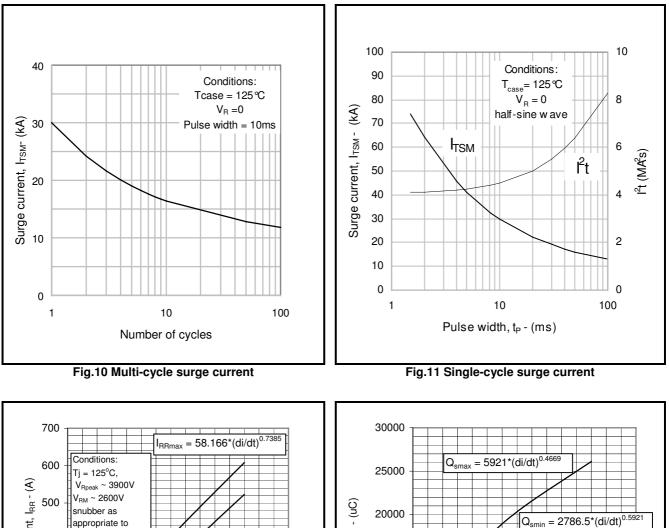
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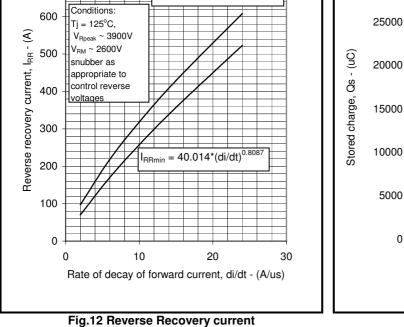
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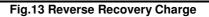
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DCR2220Y65









Rate of decay of forward current, di/dt - (A/us)

10

0 + 0

Conditions: Tj=125°C,

V_{Rpeak} ~ 3900V

V_{RM} ~ 2600V snubber as

appropriate to

20

control reverse voltages

30

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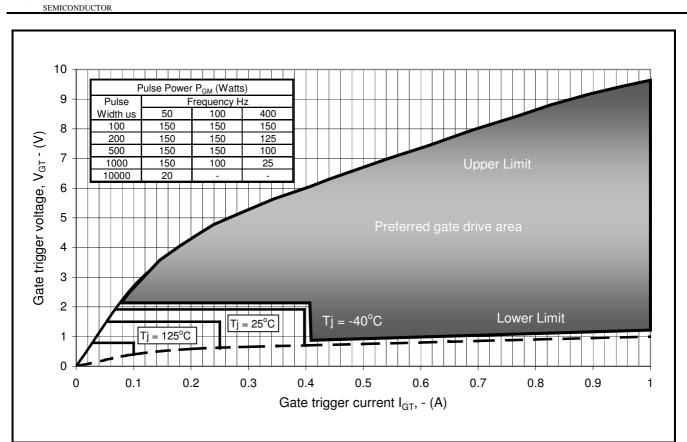


Fig14 Gate Characteristics

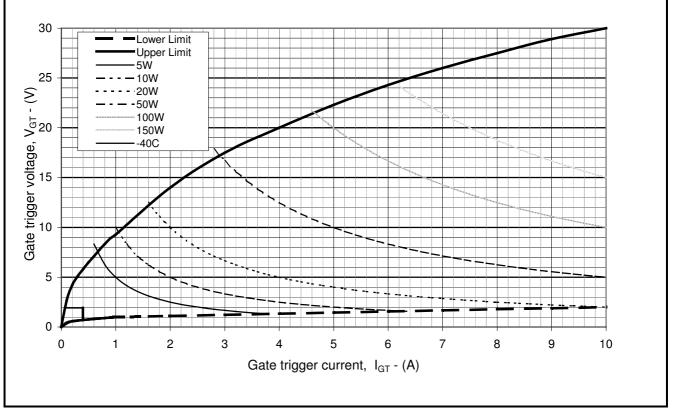


Fig. 15 Gate characteristics

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C BYNCX



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PACKAGE DETAILS

For further package information, please contact Customer Services. All dimensions in mm, unless stated otherwise. DO NOT SCALE.

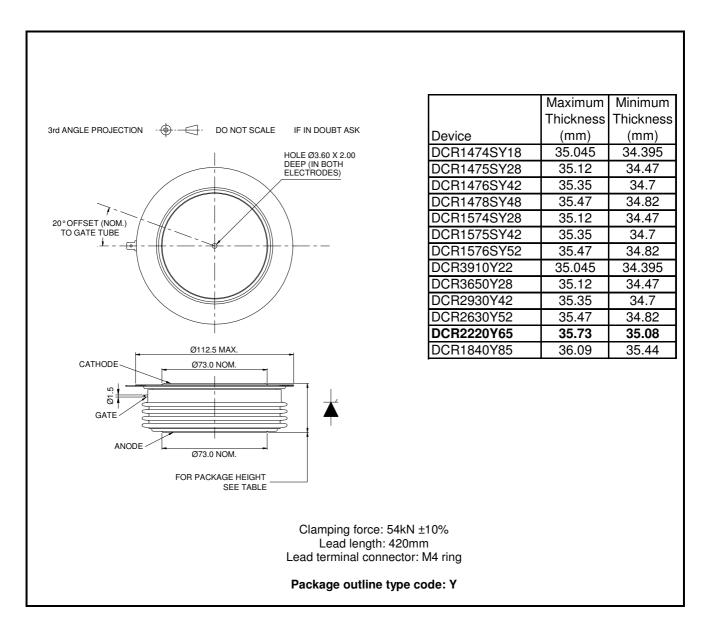


Fig.16 Package outline



POWER ASSEMBLY CAPABILITY

The Power Assembly group was set up to provide a support service for those customers requiring more than the basic semiconductor, and has developed a flexible range of heatsink and clamping systems in line with advances in device voltages and current capability of our semiconductors.

We offer an extensive range of air and liquid cooled assemblies covering the full range of circuit designs in general use today. The Assembly group offers high quality engineering support dedicated to designing new units to satisfy the growing needs of our customers.

Using the latest CAD methods our team of design and applications engineers aim to provide the Power Assembly Complete Solution (PACs).

HEATSINKS

The Power Assembly group has its own proprietary range of extruded aluminium heatsinks which have been designed to optimise the performance of Dynex semiconductors. Data with respect to air natural, forced air and liquid cooling (with flow rates) is available on request.

For further information on device clamps, heatsinks and assemblies, please contact your nearest sales representative or Customer Services.

Stresses above those listed in this data sheet may cause permanent damage to the device. In extreme conditions, as with all semiconductors, this may include potentially hazardous rupture of the package. Appropriate safety precautions should always be followed.



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